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Geological: Minerals

In the mid-late 60's EPMA began to be used in the earth sciences. A couple of groups of articles were published: one by J.V. Smith and others, mainly in the J. of Geology; Klaus Keil (now at Univ. of Hawaii) also published an article which reappeared in a variety of publications:

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- Microscopy and Microanalysis (Joint publication of many societies)
- Microbeam Analysis (Journal of the Microbeam Analysis Society, 1992-95; see J.F.)

• Yearly abstracts from MAS meetings, published as Microbeam Analysis; although in years where MAS meets together with Microscopy Society of America, the probe abstracts are merged in the meeting volume of Microscopy and Microanalysis.

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- 1) Try all variations: epma, empa, electron microprobe, electron probe, electron microanalysis
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- 3) The more traditional, applied, bibliographic databases (e.g. Georef).

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